

## 100V N-Channel Enhancement Mode MOSFET

### Description

The 60N10 uses advanced technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 100V$   $I_D = 60A$

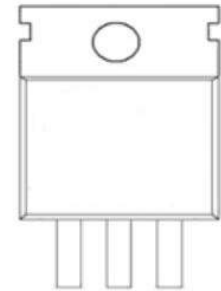
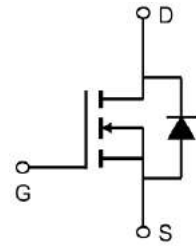
$R_{DS(ON)} < 12m\Omega$  @  $V_{GS}=10V$  (Type: 9.0m $\Omega$ )

### Application

Isolated DC

Motor control

Synchronous-rectification



### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Unit
VDS	Drain source voltage	100	V
VGS	Gate source voltage	$\pm 20$	V
ID	Continuous drain current, $T_C=25^\circ\text{C}$	60	A
IDM	Pulsed drain current, $T_C=25^\circ\text{C}$	180	A
PD	Power dissipation, $T_C=25^\circ\text{C}$	107	W
EAS	Single pulsed avalanche energy <sup>4)</sup>	183.8	mJ
Tstg, Tj	Operation and storage temperature	-55 to 150	$^\circ\text{C}$
R $\theta$ JC	Thermal resistance, junction-case	1.17	$^\circ\text{C/W}$
R $\theta$ JA	Thermal resistance, junction-ambient <sup>4)</sup>	62	$^\circ\text{C/W}$

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**Electrical Characteristics (T<sub>c</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
BVDSS	Drain-source breakdown voltage	V <sub>GS</sub> =0 V, I <sub>D</sub> =250 μA	100	111		V
VGS(th)	Gate threshold voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250 μA	1.2	1.8	2.5	V
RDS(ON)	Drain-source on-state resistance	V <sub>GS</sub> =10 V, I <sub>D</sub> =20 A		9.0	12.0	mΩ
RDS(ON)	Drain-source on-state resistance	V <sub>GS</sub> =4.5 V, I <sub>D</sub> =12 A		12	14.0	mΩ
IGSS	Gate-source leakage current	V <sub>GS</sub> =±20 V			±100	nA
IDSS	Drain-source leakage current	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V			1	uA
R <sub>G</sub>	Gate resistance	f= 1 MHz, Open drain		5.5		Ω
Ciss	Input capacitance	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=100 kHz		1998.1		pF
Coss	Output capacitance			321.7		pF
Crss	Reverse transfer capacitance			7.1		pF
td(on)	Turn-on delay time		V <sub>GS</sub> =10 V,		22.1	
t <sub>r</sub>	Rise time	V <sub>DS</sub> =50 V,		5.2		ns
td(off)	Turn-off delay time	R <sub>G</sub> =2 Ω,		44		ns
t <sub>f</sub>	Fall time	I <sub>D</sub> =25 A		8.4		ns
Q <sub>g</sub>	Total gate charge	I <sub>D</sub> =25 A, V <sub>DS</sub> =50 V, V <sub>GS</sub> =10 V		28.9		nC
Q <sub>gs</sub>	Gate-source charge			6		nC
Q <sub>gd</sub>	Gate-drain charge			6.8		nC
V <sub>plateau</sub>	Gate plateau voltage			3.7		V
I <sub>S</sub>	Diode forward current	V <sub>GS</sub> <V <sub>th</sub>			60	A
ISP	Pulsed source current				180	
VSD	Diode forward voltage	I <sub>S</sub> =20 A, V <sub>GS</sub> =0 V			1.3	V
trr	Reverse recovery time	I <sub>S</sub> =25 A, di/dt=100 A/μs		102.9		ns
Q <sub>rr</sub>	Reverse recovery charge			379		nC
I <sub>rrm</sub>	Peak reverse recovery current			6.4		A

**Note :**

- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%
- 3、 The EAS data shows Max. rating . The test condition is VDD=30V,VGS=10V, L=0.3mH, starting Tj=25°C
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation

### Typical Characteristics

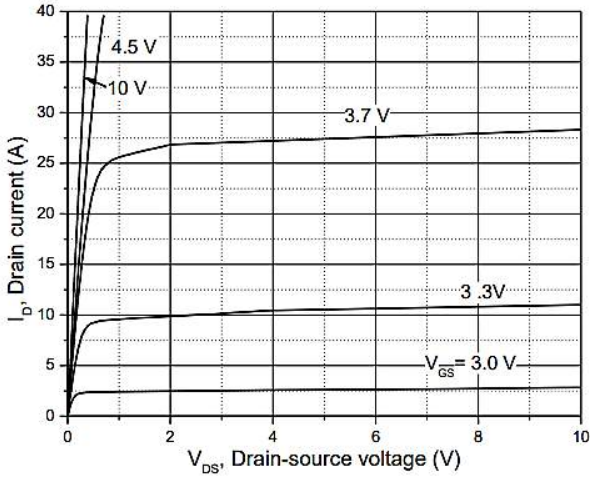


Figure 1. Typ. output characteristics

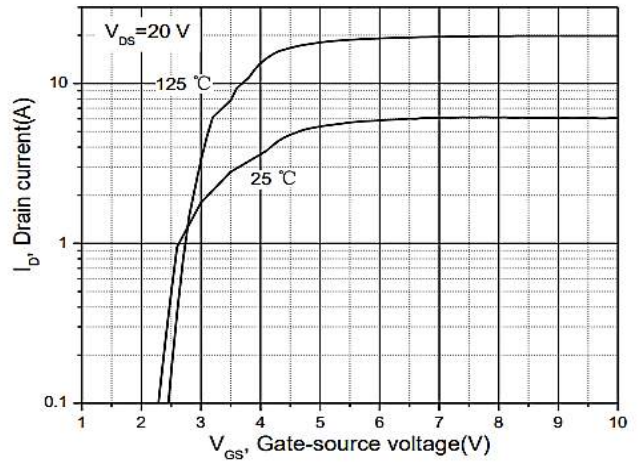


Figure 2. Typ. transfer characteristics

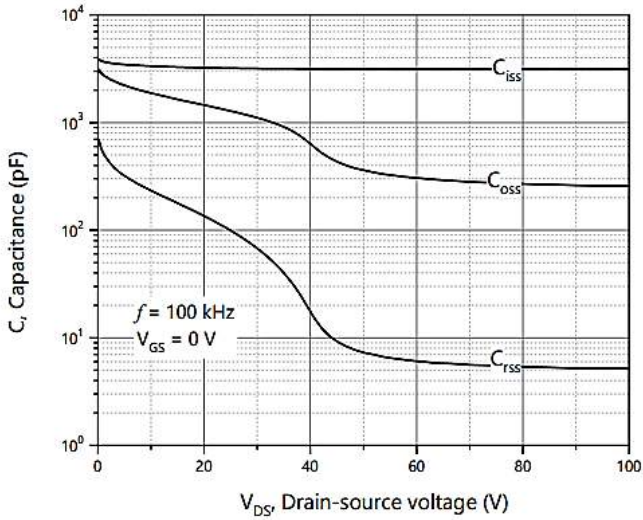


Figure 3. Typ. capacitances

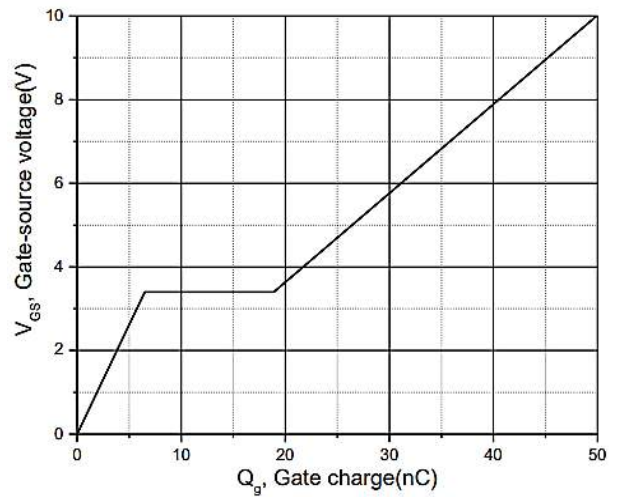


Figure 4. Typ. gate charge

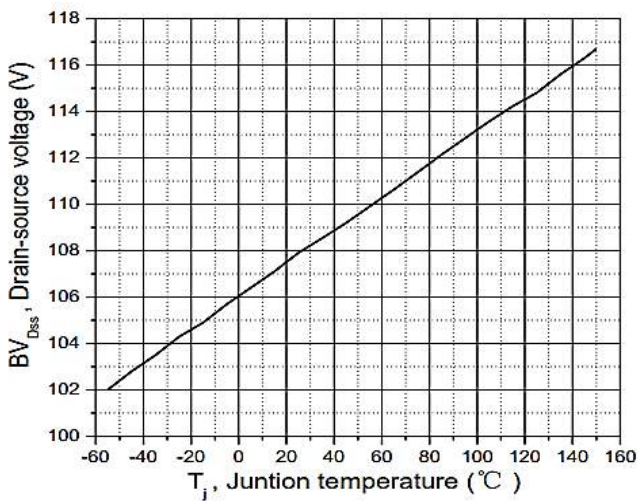


Figure 5. Drain-source breakdown voltage

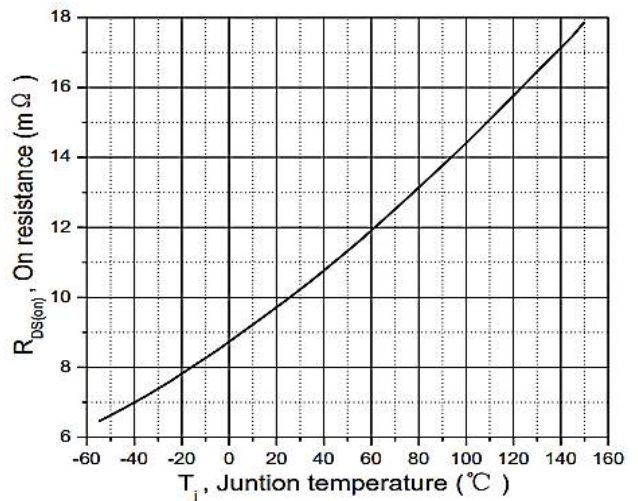


Figure 6. Drain-source on-state resistance

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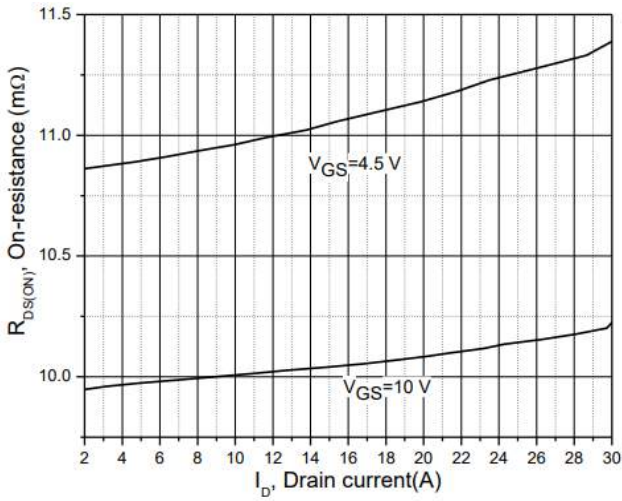


Figure 7. Drain-source on-state resistance

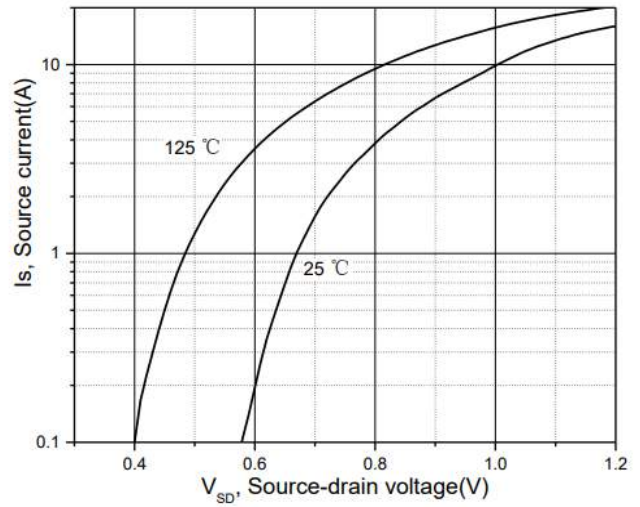


Figure 8. Forward characteristic of body diode

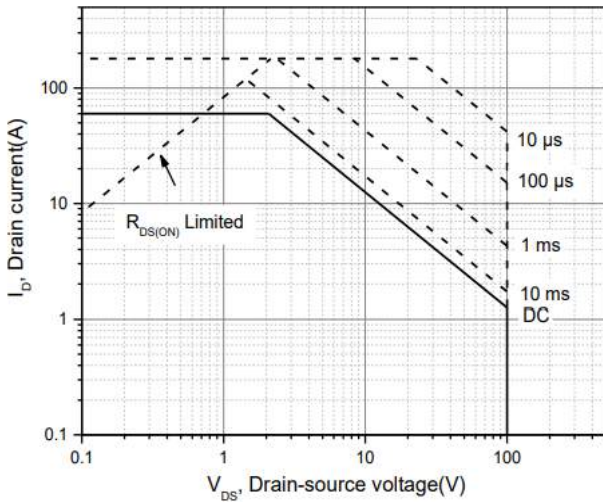


Figure 9. Safe operation area  $T_C=25\text{ }^\circ\text{C}$

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